October 2, 2011: Cheiron School 2011 @ SPring-8

Small-Angle X-ray Scattering

Basics & Applications

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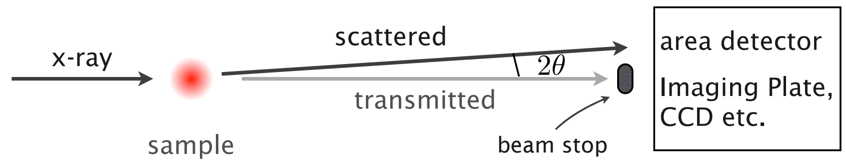
What's Small-Angle X-ray Scattering ?



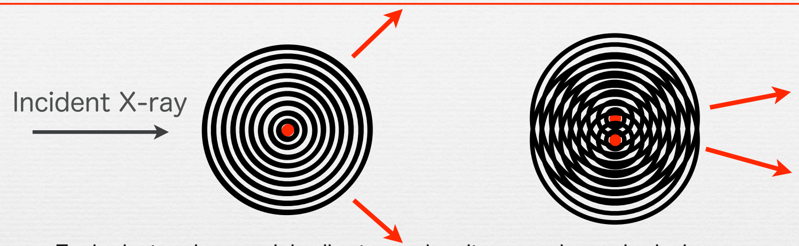
Bragg's law: $\lambda = 2d \sin\theta$

small angle → large structure (1 – 100 nm)

crystalline sample --> small-angle X-ray diffraction: SAXD

solution scattering / inhomogeneous structure --> SAXS

Interference of secondary waves



Each electron in marerials vibrates and emits secondary spherical wave

<u>When there are two electrons,</u>

- interference between secondary waves from electrons
- when a distance between electrons is small
  - --> scattering at large angle is intensified
- when a distance between electrons is large
  - --> scattering at small angle is intensified --> SAXS

History of SAXS (< 1936)

Krishnamurty (1930)

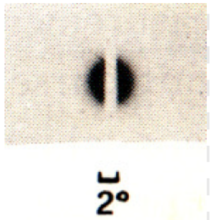
Hendricks (1932)

Mark (1932)

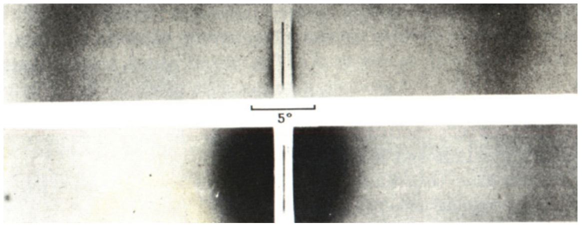
Warren (1936)

Observation of scattering

from powders, fibers, and colloidal dispersions



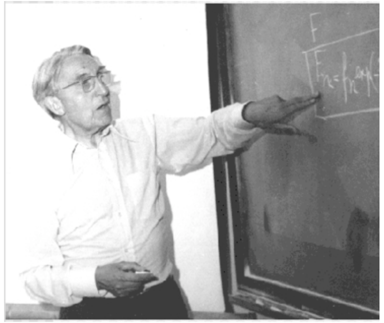
carbon black



Molten silica - silica gel

courtesy to Dr. I.L.Torriani

History (> 1936)



A. Guinier (1937, 1939, 1943)

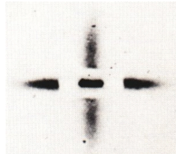
Interpretation of inhomogeneities in Al alloys "G-P zones", introducing the concept of "particle scattering" and formalism necessary to solve the problem of a diluted system of particles.

O. Kratky (1938, 1942, 1962)

G. Porod (1942, 1960, 1961)

Description of dense systems of colloidal particles, micelles, and fibers.

Macromolecules in solution.

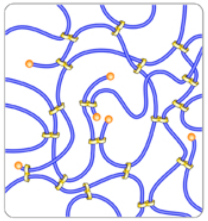


Single crystals of Al-Cu hardened alloy

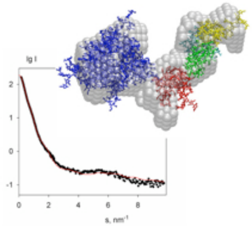
Hemoglobin

courtesy to Dr. I.L.Torriani

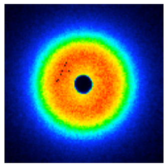
Application of SAXS



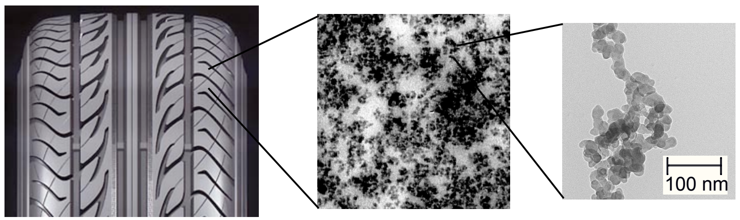
gel



Proteins in solution (Dr. Svergun, EMBL)



Typical SAXS image



Nanocomposite

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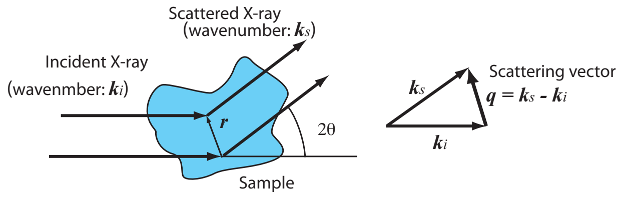
Basic of X-ray scattering



$\rho(\boldsymbol{r})$: electron density

$q = |\boldsymbol{q}| = 4\pi \sin\theta / \lambda$

Amplitude of scattered X-ray $A(\boldsymbol{q}) = \int_V \rho(\boldsymbol{r}) \exp(-i\boldsymbol{q}\cdot\boldsymbol{r}) d\boldsymbol{r}$

Fourier transform of electron density

Scattering intensity per unit volume: $I(\boldsymbol{q}) = \dfrac{A(\boldsymbol{q})A^*(\boldsymbol{q})}{V}$

Intensive variables don't depend on the system size (volume).
Extensive variables depend on the system size (volume).

Real space and Reciprocal Space

Real Space

Electron Density

$\rho(\boldsymbol{r})$

Autocorrelation

$\gamma(\boldsymbol{r})$

Autocorrelation Function

Fourier Trans.

Inv. Fourier Trans.

Reciprocal Space

Scattering amplitude

$A(q)$

Squaring

$I(q)$

Scattering Intensity

= Patterson Function per volume

Autocorrelation Function & Scattering Intensity

Autocorrelation function of electron density per unit volume

$$\gamma(\boldsymbol{r}) = \frac{1}{V}\int_V \rho(\boldsymbol{r}')\rho(\boldsymbol{r}+\boldsymbol{r}')d\boldsymbol{r}' = \frac{1}{V}P(\boldsymbol{r})$$

Patterson Function

(Debye & Bueche 1949)

asymptotic behavior of the autocorrelation function

$$\gamma(0) = \langle\rho^2\rangle \qquad \gamma(\infty) = \langle\rho\rangle^2$$

Scattering Intensity : Fourier Transform of autocorrelation function

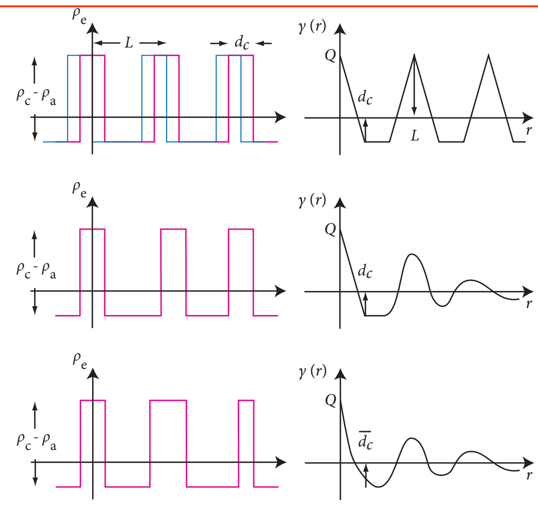
$$I(\boldsymbol{q}) = \int_V \gamma(\boldsymbol{r}) \exp(-i\boldsymbol{q}\cdot\boldsymbol{r}) d\boldsymbol{r}$$

ρ(r) & γ(r) of lamellar structure

ideal ordering

Long period changes.

Thickness of crystal changes.



real space

autocorrelation

Normalized Autocorrelation Function:

Introducing the relative electron density, $\eta(\boldsymbol{r})$, as

$$\eta(\boldsymbol{r}) = \rho(\boldsymbol{r}) - \langle\rho\rangle \longrightarrow \langle\eta^2\rangle = \langle(\rho(\boldsymbol{r}) - \langle\rho\rangle)^2\rangle = \langle\rho^2\rangle - \langle\rho\rangle^2$$

Introducing the normalized autocorrelation function, $\gamma_0(\boldsymbol{r})$, as

$$\langle\eta^2\rangle\gamma_0(\boldsymbol{r}) = \frac{1}{V}\int_V \eta(\boldsymbol{r}')\eta(\boldsymbol{r}+\boldsymbol{r}')\mathrm{d}\boldsymbol{r}'$$

then, $\gamma_0(\boldsymbol{r}) = \dfrac{\gamma(\boldsymbol{r}) - \langle\rho\rangle^2}{\langle\eta^2\rangle}$ where $\gamma_0(0) = 1 \quad \gamma_0(\infty) = 0$

$$\boxed{I(\boldsymbol{q}) = \langle\eta^2\rangle \int_V \gamma_0(\boldsymbol{r})e^{-\mathrm{i}\boldsymbol{q}\cdot\boldsymbol{r}}\mathrm{d}\boldsymbol{r} + \langle\rho\rangle^2\delta(\boldsymbol{q})}$$

The average density fluctuations determine the magnitude of I(q). The normalized autocorrelation function γ_0(r) determines the shape of I(q).

Not observable.

Invariant Q

Invariant: $Q = \int_0^\infty I(q)q^2\mathrm{d}q = 2\pi^2\langle\eta^2\rangle$

doesn't depend on the structure

$(\because)$

$$\boxed{I(\boldsymbol{q}) = \langle\eta^2\rangle \int_V \gamma_0(\boldsymbol{r})e^{-\mathrm{i}\boldsymbol{q}\cdot\boldsymbol{r}}\mathrm{d}\boldsymbol{r} + \langle\rho\rangle^2\delta(\boldsymbol{q})}$$

Omitted.

Parseval's theorem

$$\int I(\boldsymbol{q})\mathrm{d}\boldsymbol{q} = (2\pi)^3\langle\eta^2\rangle$$

$$4\pi\int I(q)q^2\mathrm{d}q$$

Parseval's theorem

$$A(\boldsymbol{q}) \xleftrightarrow{\text{Fourier Trans.}} \eta(\boldsymbol{r})$$

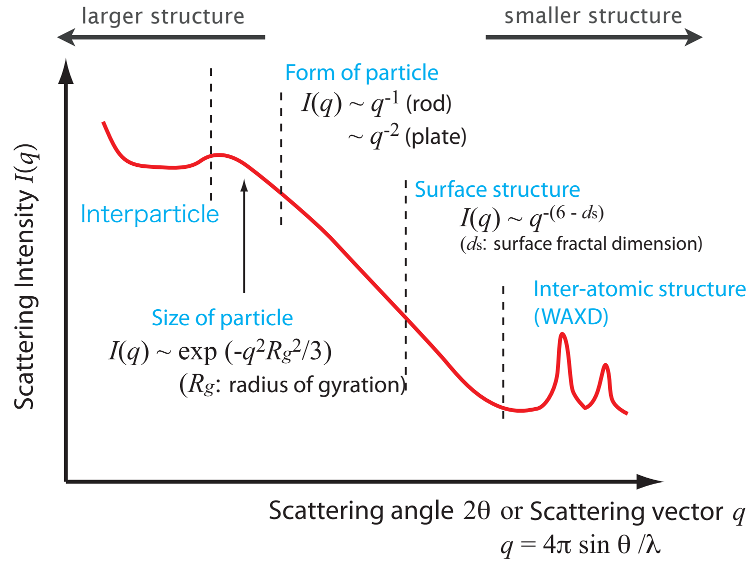
$$\int |A(\boldsymbol{q})|^2\,\mathrm{d}\boldsymbol{q} = (2\pi)^3\int |\eta(\boldsymbol{r})|^2\,\mathrm{d}\boldsymbol{r}$$

Information obtained from SAXS

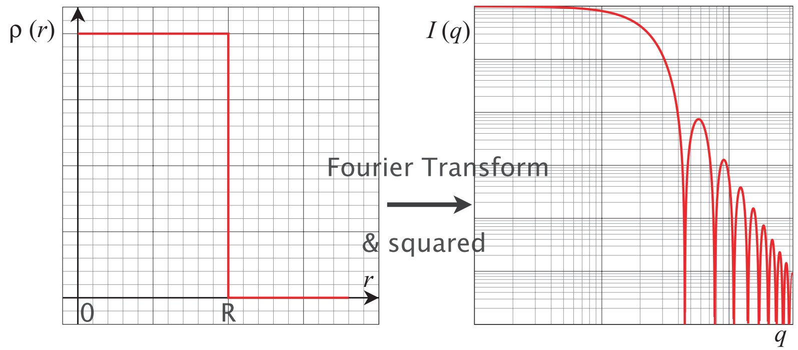
1. Size and form of particulate system
   - Colloids, Globular proteins, etc...
2. Correlation length of inhomogeneous structure
   - Polymer chain, two-phase system etc.
3. Lattice parameters of distorted crystals (para-crystal)
4. Degree of crystallinity, crystal size, crystal distortion
   - Crystalline polymer

SAXS of particulate system

Relation between SAXS pattern and Structural information



Spherical sample

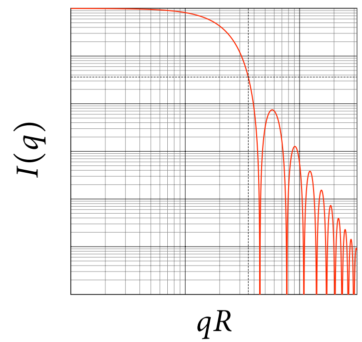


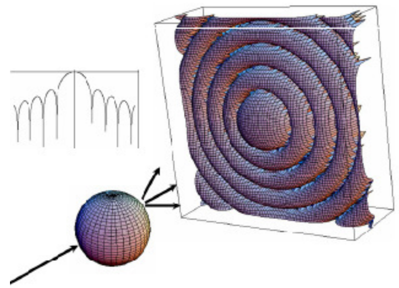
$$\rho(r) = \begin{cases} \Delta\rho & r < R \\ 0 & \text{else} \end{cases}$$

$$I(q) = \frac{(\Delta\rho)^2 V_{\text{particle}}^{\ 2}}{V} \left[3 \frac{\sin qR - qR \cos qR}{(qR)^3} \right]^2$$

Homogeneous sphere

$$I(q) = \frac{(\Delta\rho)^2 V_{\text{particle}}^{\ 2}}{V} \left[3 \frac{\sin qR - qR \cos qR}{(qR)^3} \right]^2$$





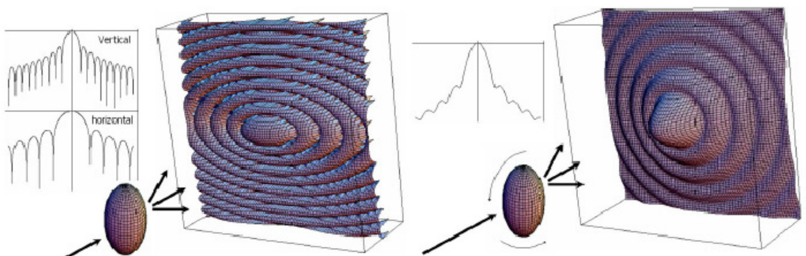
isotropic scattering

courtesy to Dr. I.L.Torriani

Homogeneous elipsiod

Fixed particle

Random orientation

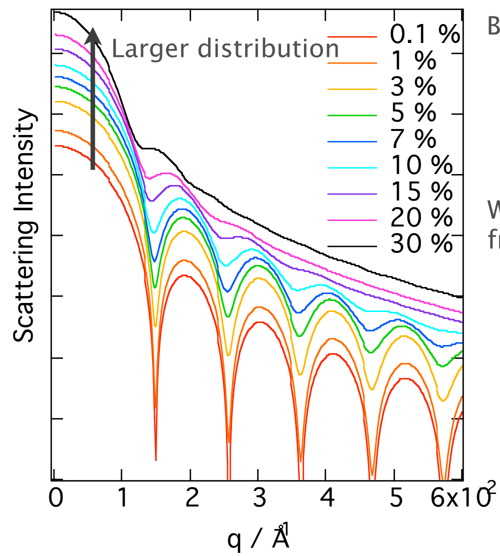


anisotropic scattering

isotropic scattering

courtesy to Dr. I.L.Torriani

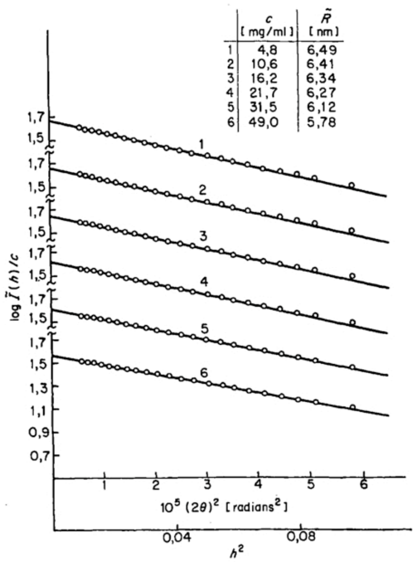
Size distribution



Based on Gaussian distribution

When the form has distribution, fringes are missed.

Radius of Gyration -- Guinier Plot



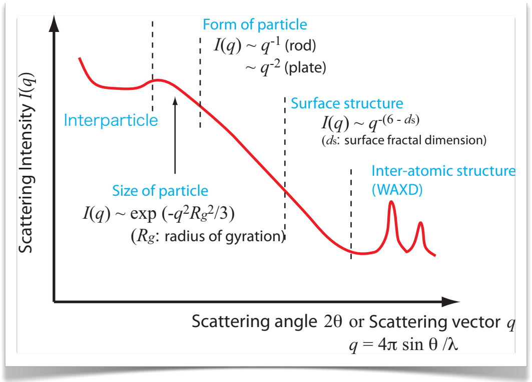
$$I(q) \sim \exp\left(-\frac{q^2 {R_g}^2}{3}\right)$$

$$\log\left(I(q)\right) = -\frac{q^2 {R_g}^2}{3}$$

Guinier plot: log ($I(q)$) vs q^2

O. Glatter & O. Kratky ed., "Small Angle X-ray Scattering", Academic Press (1982).

Structure Factor & Form Factor



$$I(q) = \phi V_{\text{particle}} S(q) F(q)$$

Structure Factor → inter-particle structure

Form Factor → intra-particle structure

Separation of S(q) & F(q)

→ Everlasting issue

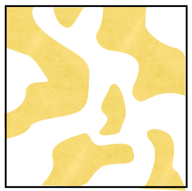
(especially, for non-crystalline sample)

Proposed remedy:

- GIFT (Generalized Inverse Fourier Trans.) by O. Glatter

Scattering from Inhomogeneous Structure

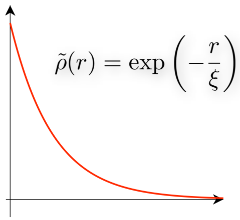
Electron Density | Autocorrelation Function | Scattering Intensity

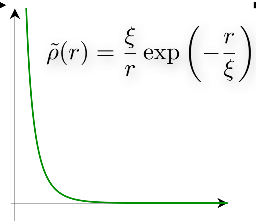


two phase system

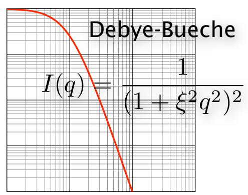
polymer chain etc.

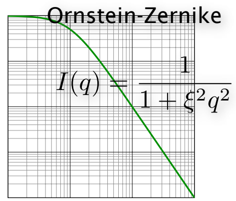
Autocorrelation →





Fourier trans. →





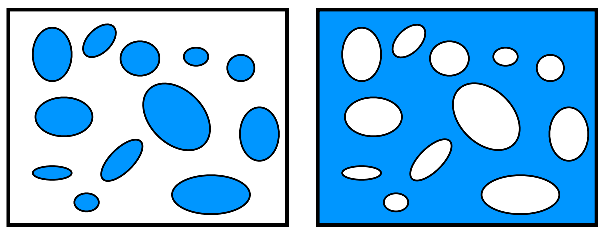
Two-phase system

Phase 1: ρ_1, volume fraction ϕ Phase 2: ρ_2 volume fraction $1-\phi$

$$A(\boldsymbol{q}) = \int_{\phi V} \rho_1 e^{-i\boldsymbol{q}\cdot\boldsymbol{r}} d\boldsymbol{r} + \int_{(1-\phi)V} \rho_2 e^{-i\boldsymbol{q}\cdot\boldsymbol{r}} d\boldsymbol{r}$$

$$= \int_{\phi V} (\rho_1 - \rho_2) e^{-i\boldsymbol{q}\cdot\boldsymbol{r}} d\boldsymbol{r} + \rho_2 \int_V e^{-i\boldsymbol{q}\cdot\boldsymbol{r}} d\boldsymbol{r}$$

$$\boxed{A(\boldsymbol{q}) = \int_V \Delta\rho\, e^{-i\boldsymbol{q}\cdot\boldsymbol{r}} d\boldsymbol{r} + \rho_2 \delta(\boldsymbol{q})}$$



Babinet's principle

Two complementary structures produce the same scattering.

Two-phase system -- cont.

Averaged square fluctuation of electron density

$$\langle \eta^2 \rangle = \phi(1-\phi)(\Delta\rho)^2 \qquad \text{where} \qquad \Delta\rho = \rho_1 - \rho_2$$

Φ : volume fraction

$$I(q) = 4\pi \langle \eta^2 \rangle \int_0^\infty \gamma_0(r) \frac{\sin(qr)}{qr} r^2 \mathrm{d}r$$

$$I(q) = 4\pi\phi(1-\phi)(\Delta\rho)^2 \int_0^\infty \gamma_0(r) \frac{\sin(qr)}{qr} r^2 \mathrm{d}r$$

$$\boxed{Q = \int_0^\infty I(q) q^2 \mathrm{d}q = 2\pi^2 \phi(1-\phi)(\Delta\rho)^2}$$

Invariant: does not depend on the structure of the two phases but only on the volume fractions and the contrast between the two phases.

Porod's law

For a sharp interface, the scattered intensity decreases as q^{-4}.

$$I(q) \to (\Delta\rho)^2 \frac{2\pi}{q^4} \underline{S}/V$$

internal surface area

Combination of Porod's law & Invariant Q

$$\pi \cdot \frac{\lim_{q\to\infty} I(q) q^4}{Q} = \boxed{\frac{S}{V}}$$

surface-volume ratio

important for the characterization of porous materials

Pair Distance Distribution Function: PDDF

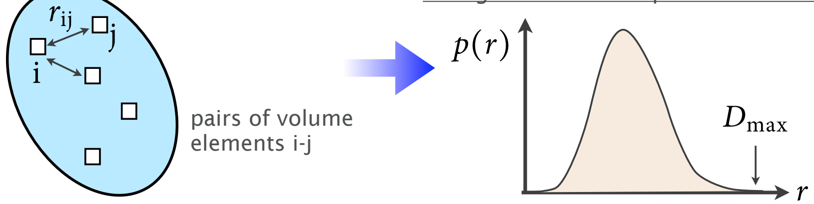
Scattering intensity: $I(q) = 4\pi \int_0^\infty \gamma_0(r) \frac{\sin(qr)}{qr} r^2 \mathrm{d}r$
(when isotropic)

PDDF : $p(r) = r^2 \gamma_0(r)$

the set of distances joining the volume elements within a particle, including the case of non-uniform density distribution.

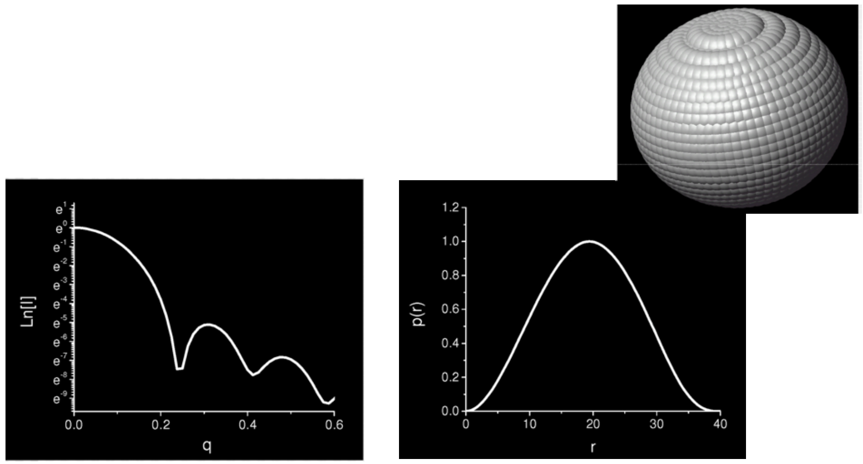
Particle's SHAPE and maximum DIMENSION.

histogram of all intra-particle distances



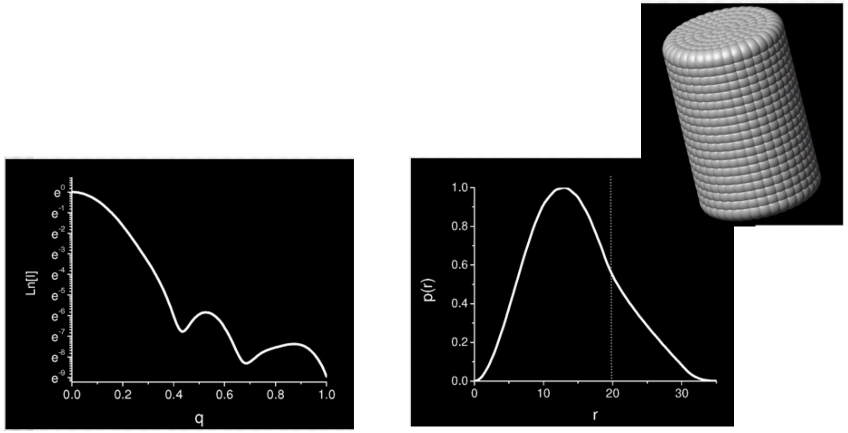
$$I(q) = 4\pi \int_0^\infty p(r) \frac{\sin(qr)}{qr} \mathrm{d}r$$

I(q) & P(r) of Spherical particle



courtesy to Dr. I.L.Torriani

I(q) & P(r) of Cylindrical particle



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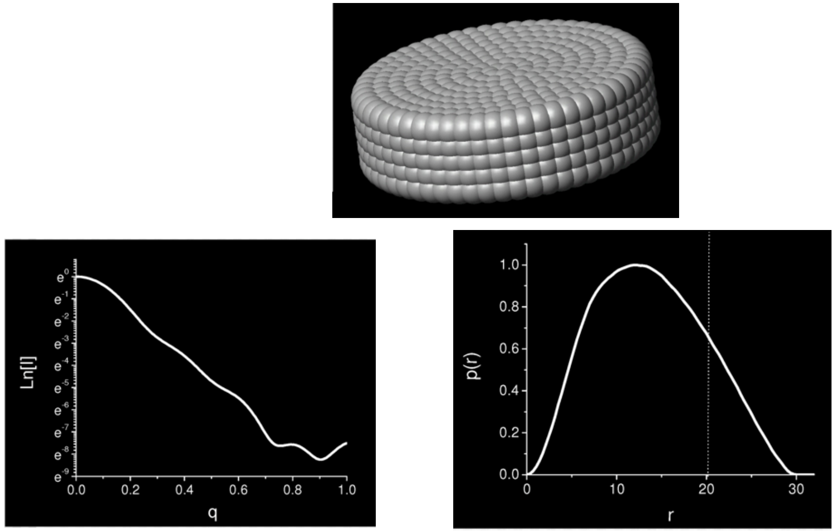
I(q) & P(r) of Flat particle



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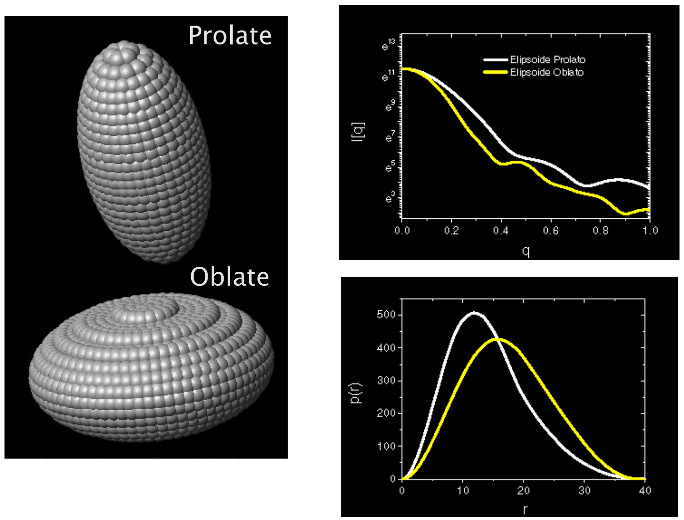
I(q) & P(r) of Ellipsoids



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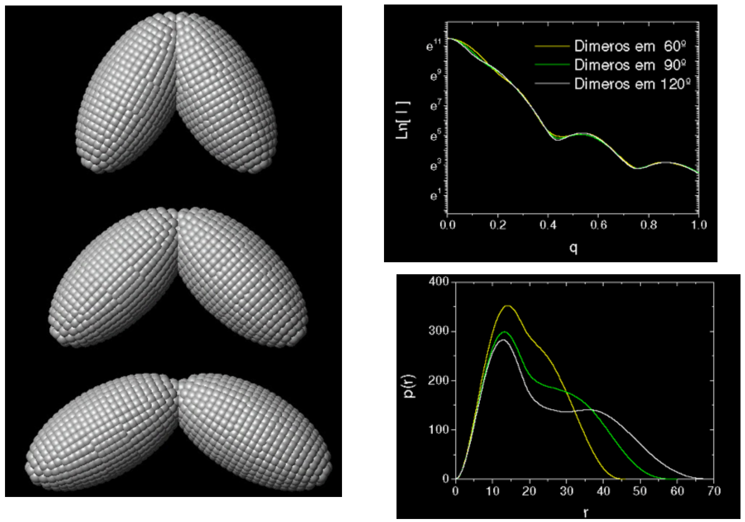
I(q) & P(r) of Two ellipsoid = dimer



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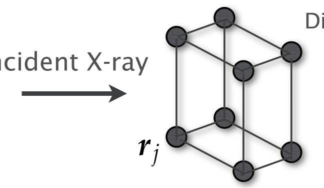
Diffraction from Periodic Structure

Incident X-ray



Diffraction from Unit cell (Crystalline structure factor)

$$F(q) = \sum_j f(q)\exp(-iq \cdot r_j)$$

$f(q)$: Atomic Form Factor

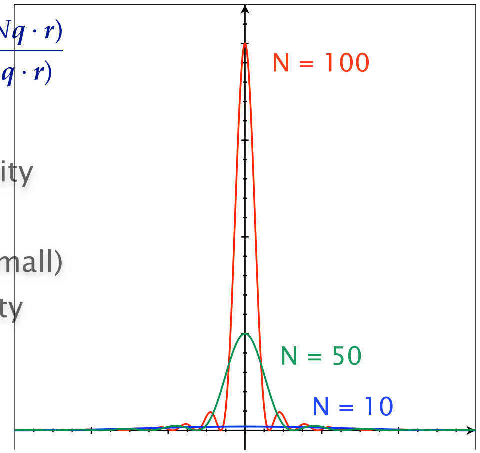
Diffraction Intensity: $I(q) \sim |G(q)|^2 |F(q)|^2$

Laue function: $|G(q)|^2 = \dfrac{\sin^2(\pi N q \cdot r)}{\sin^2(\pi q \cdot r)}$

- Maximum ~ N^2
- FWHM ~ $2\pi/N$
  - FWHM --> Size of crystal

Laue Function

Laue function: $|G(q)|^2 = \dfrac{\sin^2(\pi N q \cdot r)}{\sin^2(\pi q \cdot r)}$

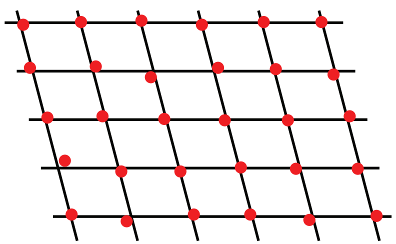


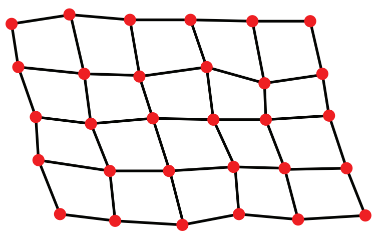
- Large crystal
  - High diffraction intensity
  - Narrow FWHM
- Soft matter (crystal size: small)
  - Low diffraction intensity
  - Wide FWHM

→ low S/N

Crystal size --> Intensity & FWHM of diffraction

Imperfection of crystal (2D)





Imperfection of 1st kind

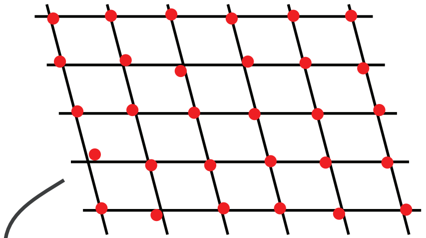
Thermal fluctuation etc.

Imperfection of 2nd kind

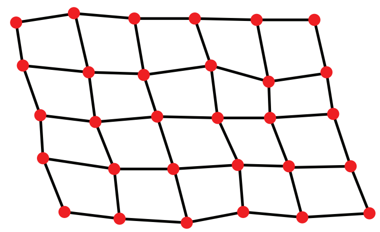
in the case of soft matter

Imperfection of crystal

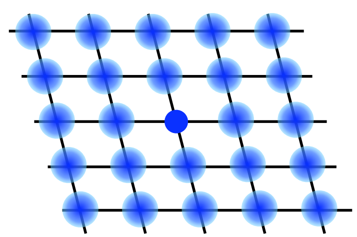
Imperfection of 1st kind

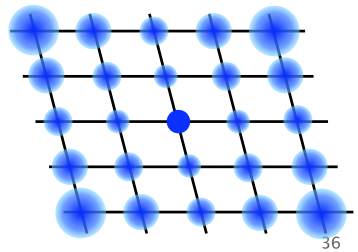


Imperfection of 2nd kind



Autocorrelation



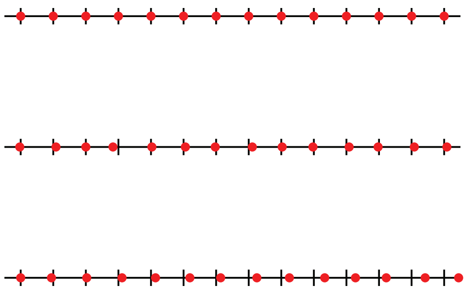


Imperfection of lattice (1D)

Perfect lattice

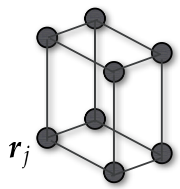
Imperfection of 1st kind

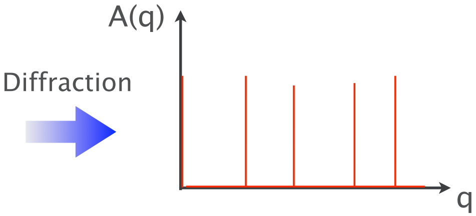
Imperfection of 2nd kind



- Effect of imperfections on diffraction ?

Diffraction from lattice-structure





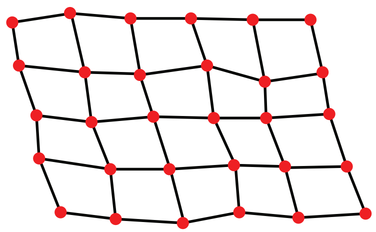
$$\rho(\boldsymbol{r}) = \rho_u(\boldsymbol{r}) * \underline{z(\boldsymbol{r})} \qquad A(\boldsymbol{q}) = F(\boldsymbol{q}) \cdot \underline{Z(\boldsymbol{q})}$$

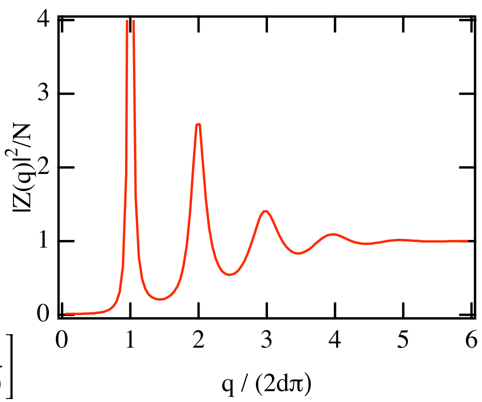
convolution

Form of lattice

z(**r**) with imperfection ---> calculate Z(**q**)

Imperfection of 2nd kind





Paracrystal theory

$$|Z(q)|^2 = N\left[1 + \frac{P(q)}{1-P(q)} + \frac{P^*(q)}{1-P^*(q)}\right]$$

Decrease of diffraction intensity and
Increase of FWHM

R. Hosemann, S. N. Bagchi, Direct Analysis of Diffraction
by Matter, North-Holland, Amsterdam (1962).

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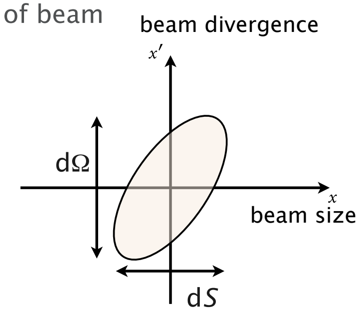
X-ray Source for SAXS

Emittance -- Product of size and divergence of beam

$$\text{Brilliance} = \frac{d^4 N}{dt \cdot d\Omega \cdot dS \cdot d\lambda/\lambda}$$

[photons/(s·mrad²·mm²·0.1% rel.bandwidth)]

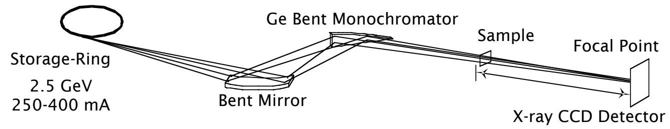


SAXS needs to use a low divergence and small beam

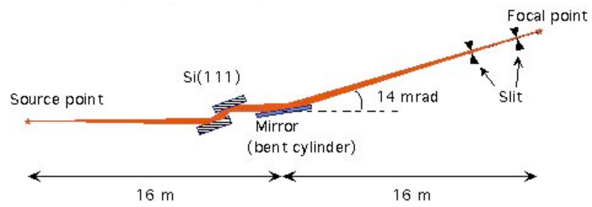
→ High brilliance beam is required !

X-ray Optics for SAXS

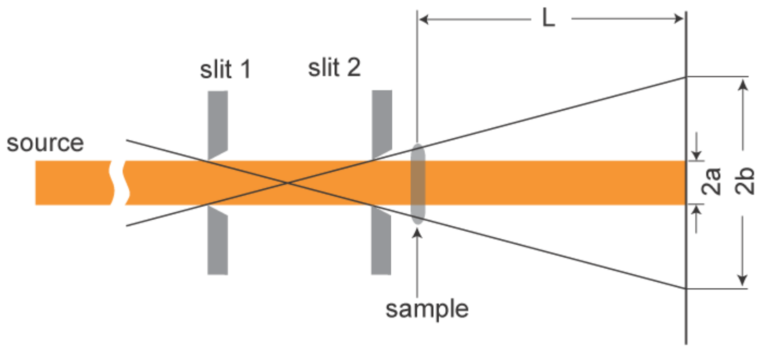
PF BL-15A



PF BL-10C



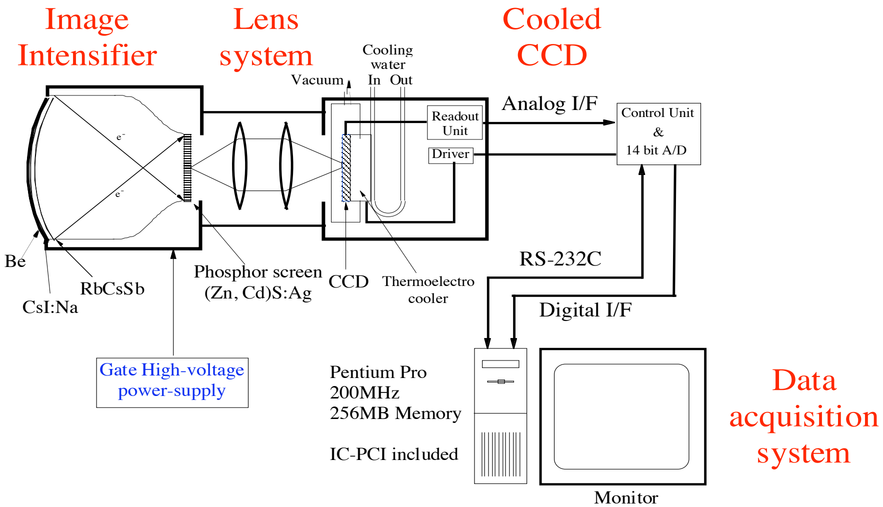
Slits for SAXS



Detectors for SAXS

	Good Point	Drawback
PSPC	• time-resolved • photon-counting • low noise	• counting-rate limitation
Imaging Plate	• wide dynamic range • large active area	• slow read-out
CCD with Image Intensifier	• time-resolved • high sensitivity	• image distortion • low dynamic range
Fiber-tapered CCD	• fast read-out • automated measurement	• not good for time-resolved

X-ray CCD detector with Image Intensifier



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Advanced SAXS

SAXS

Microbeam X-ray
- Inhomogeneity of nano-structure
- local time evolution of structure

Time-resolved
- time evolution of structure

GI-SAXS
- surface, interface, thin films

XPCS
- structural fluctuation
- dynamics

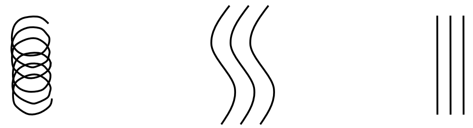
Combined measurement with DSC, viscoelasticity

wide-q (USAXS-SAXS-WAXS)
- hierarchical structure

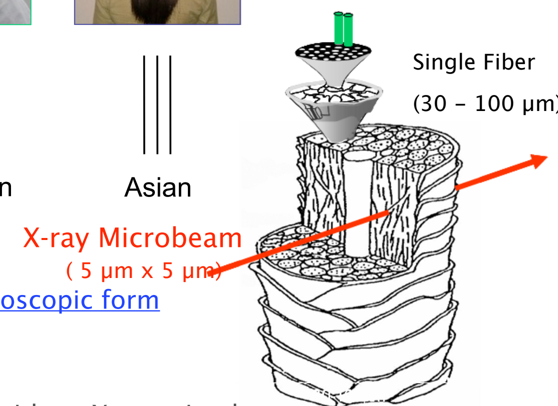
2D measurement
- anisotropic structure

Application of paracrystal theory

Collab. with Kao ltd.



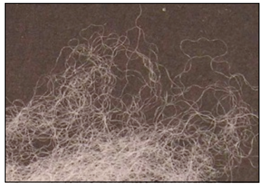
African Caucasian Asian



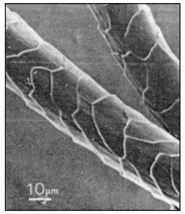
Relationship between macroscopic form and microscopic structure?

Local observation with an X-ray microbeam

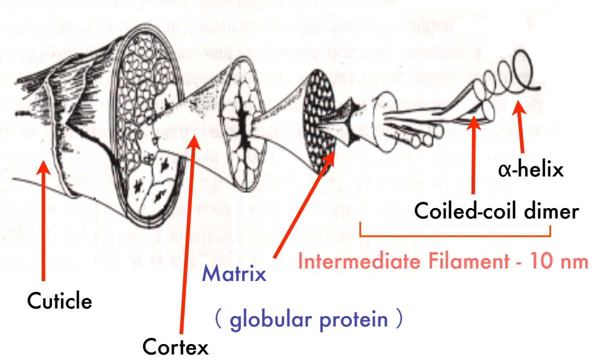
Internal structure of wool



SEM 像



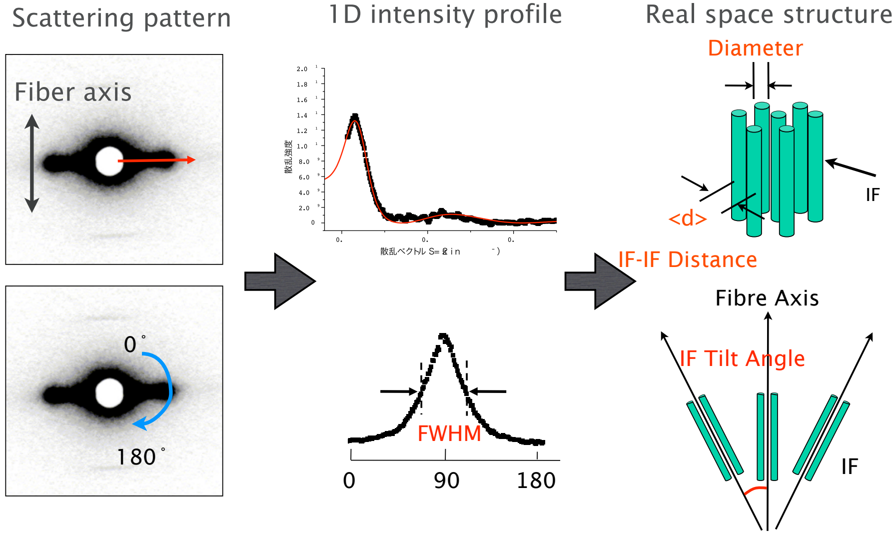
H. Ito et al., Textile Res. J. **54**, 397–402 (1986).



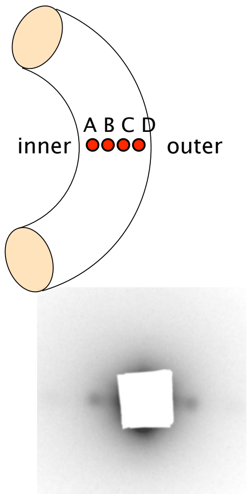
R. D. B. Fraser et al., Proc. Int. Wool Text. Res. Conf., Tokyo, II, **37**, (1985) partially changed.

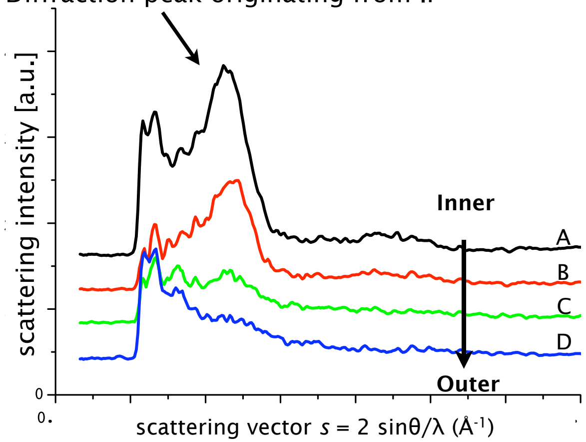
Relationship between IF distribution and hair curlness?

Structure of Intermediate Filament

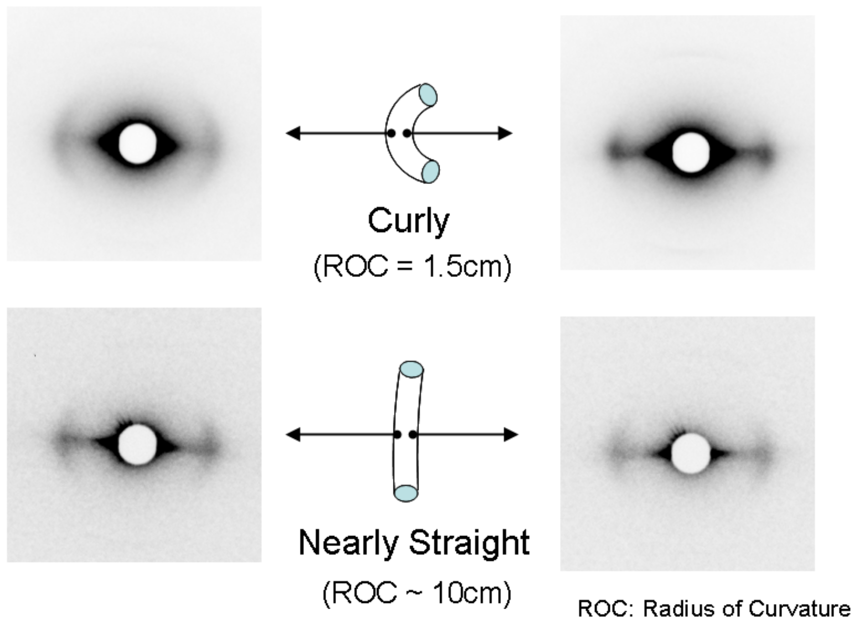


Diffraction intensity profiles

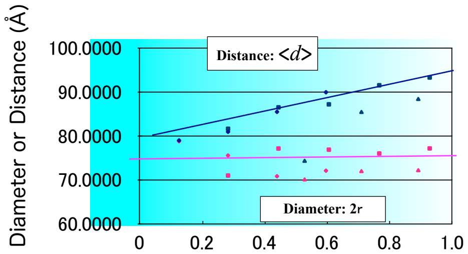




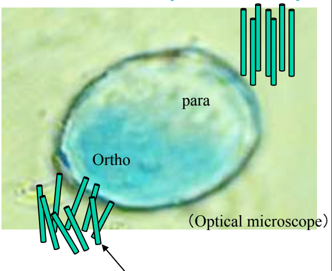
Difference in diffraction intensity
--> Structural difference in cortex.



Distribution of Intermediate Filament (IF)

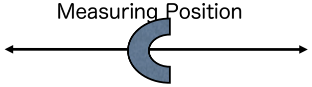


Stained with Methylene blue dye



Outer side of fiber curve

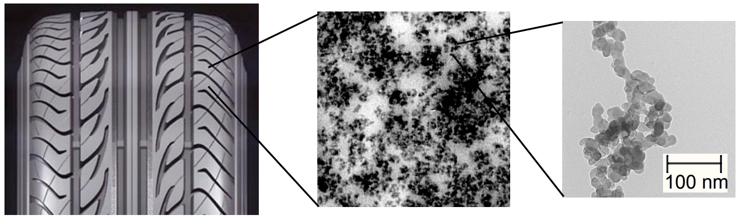
Measuring Position



Inner side of fiber curve

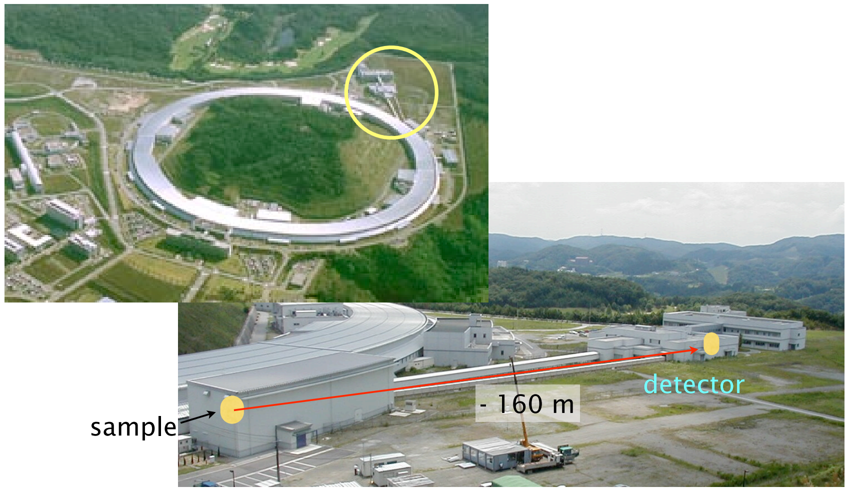
- Diameter of Intermediate filament (IF) is almost constant
- Distance between IFs increases from outer to inner sides.

USAXS for nano-composite in rubber

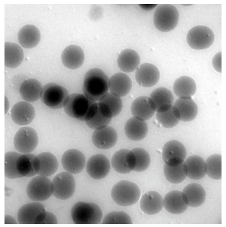


Nanocomposite

USAXS using medium-length beamline

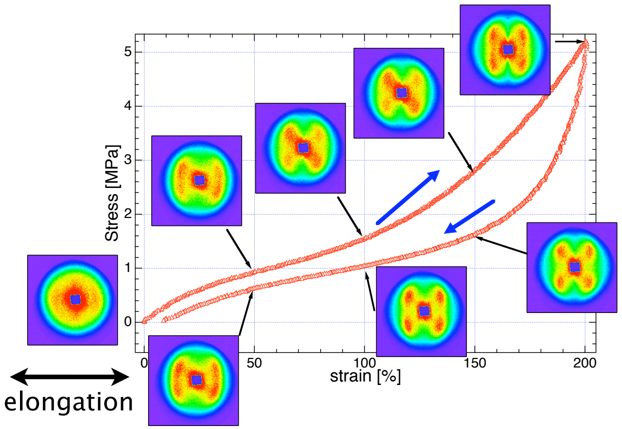


USAXS patterns from elongated rubber



TEM image

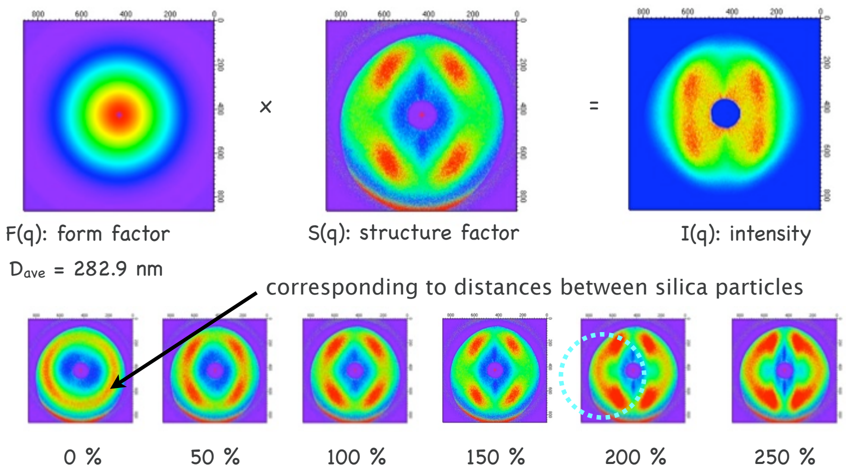
Rubber filled with spherical silica



Scattering pattern also shows hysteresis.

Y. Shinohara et al., J. Appl. Cryst., **40**, s397 (2007).

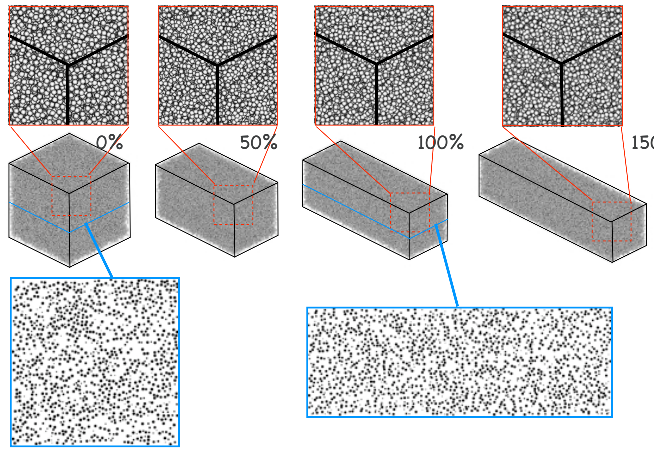
Separation of Structure factor S(q)



Y. Shinohara et al., J. Appl. Cryst., **40**, s397 (2007).

Analysis by RMC (Reverse Monte Carlo)

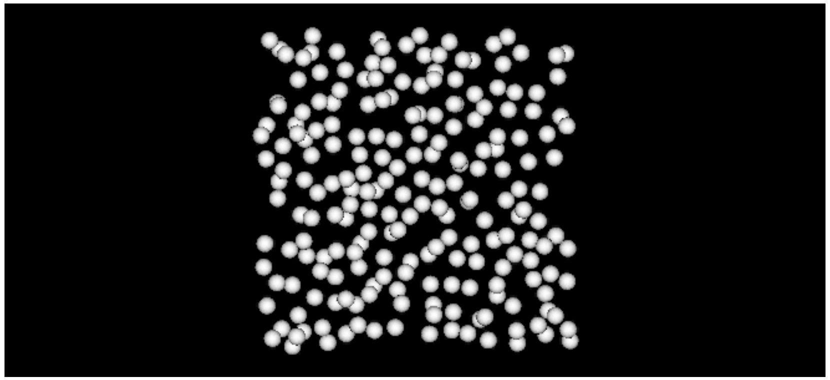
Sample：monodispersive silica spheres in rubber



Courtesy to Dr.Hagita & Prof. Arai

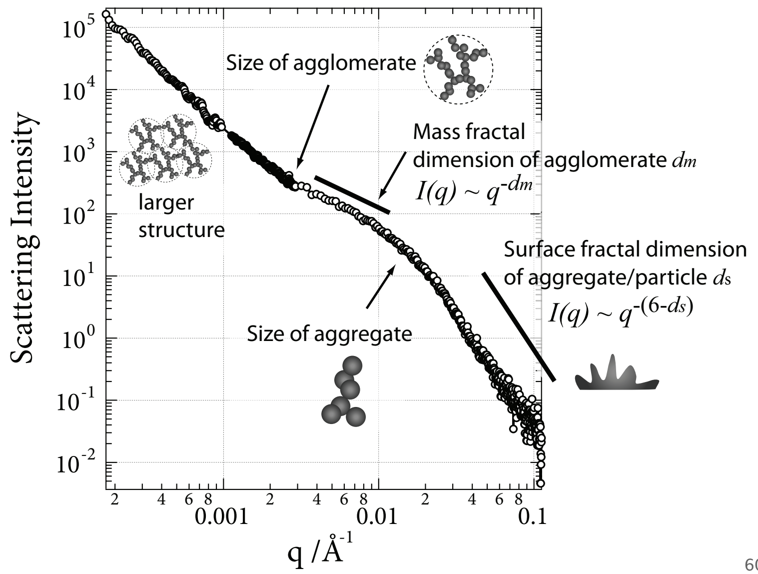
Visualization of structure change of fillers during elongation of rubber by using SAXS and RMC

0→150% : elongation process



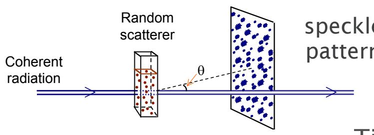
non-uniformity increases along the elongation direction.

Structural information from USAXS



X-ray Photon Correlation Spectroscopy: XPCS

- Measurement of fluctuation of X-ray scattering intensity
  --> Structural fluctuation in sample

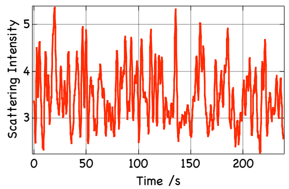


speckle pattern

$$g^{(2)}(q,\tau) = \frac{\langle I(q,0)I^{*}(q,\tau)\rangle}{\langle I(q)\rangle^{2}}$$

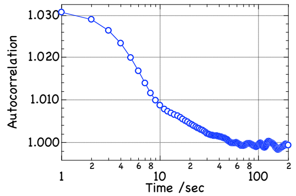
Time-resolved SAXS with coherent X-ray

Fluctuation of intensity

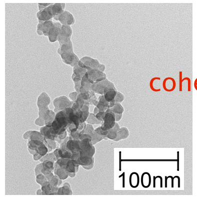


Autocorrelation

relaxation time in system

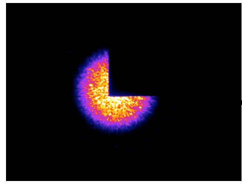


Dynamics of nanoparticles observed with XPCS

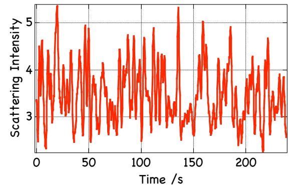


coherent x-ray

nano-particles in rubber



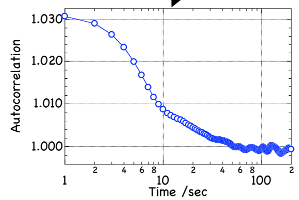
speckle pattern



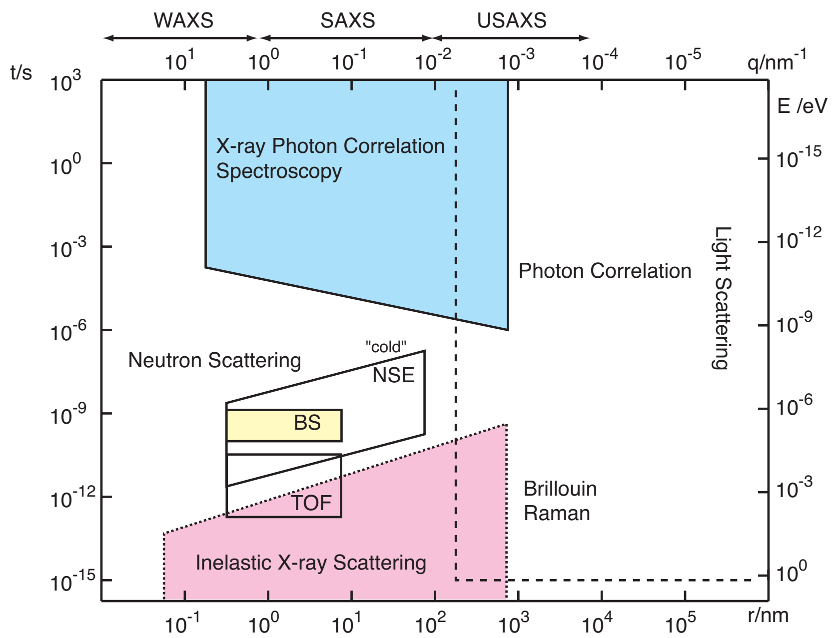
fluctuation of scattering intensity

Dependence of dynamics on...

- Volume fraction of nano-particles
- Vulcanization (cross-linking)
- Type of nano-particles
- Temperature etc.



Dynamics of Filler in Rubber



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